

Notice of References Cited	Application/Control No. 10/710,766	Applicant(s)/Patent Under Reexamination NIEH ET AL.	
	Examiner Christopher B. Shin	Art Unit 2181	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,958,277	09-1990	Hill et al.	710/52
*	C	US-6,331,784	12-2001	Mason et al.	326/8
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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